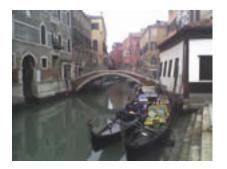


UIE working group Power Quality

Voltage Dip Immunity of Equipment and Installations



The First International Conference on Smart Grids, Green Communications and IT Energy-aware Technologies

ENERGY 2011

May 22-27, 2011 - Venice/Mestre, Italy

TUTORIAL

Equipment and Processes Immunity (Part 3)



Equipment/Process Dip Immunity

Review of equipment behaviour and responses to voltage dips

- What is reported in literature?
- Experience of Working Group members
- Is the information complete?
- How this information should be presented?

Overview of process immunity

- How do typical processes react to dips?
- Identification of the most critical equipment



Equipment Behaviour

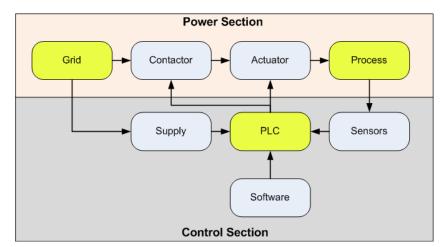
Parameters of influence:

- Voltage supply related parameters
 - Pre-dip: voltage magnitude, distortion, unbalance...
 - During-dip: dip type, shape, depth, duration, segments...
 - Post-dip: voltage recovery, inrush current, distortion...
 - Network topology: source impedance, presence of other equipment
- Equipment specific parameters
 - Hardware topology, operation mode, parameter settings, loading
- Non-electrical parameters
 - Temperature, humidity, presence of vibrations...



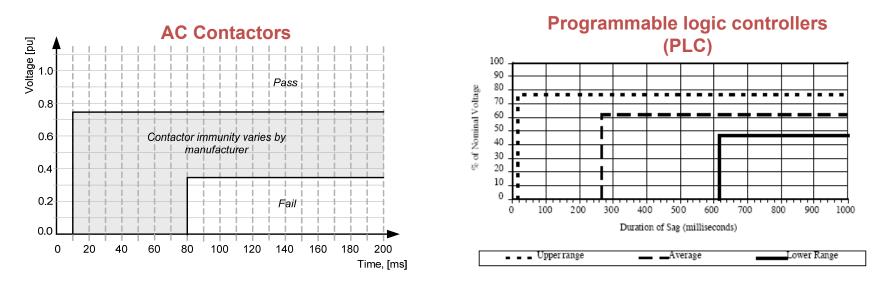
Equipment Behaviour

- □ As mentioned, lot of parameters involved
- Each piece of equipment can be considered unique (together with its environment)
- Single representation, using e.g. a voltage tolerance curve, is often not sufficient
- Literature mainly focuses on dip parameters
- $\Box \text{ Example Process } \rightarrow$



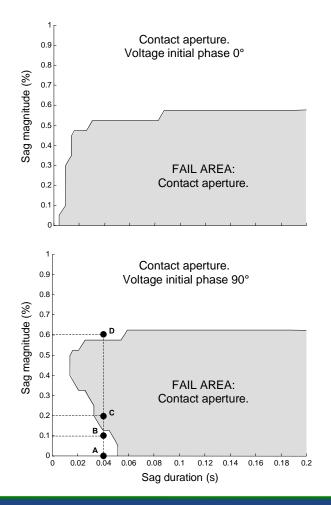


"Best and Worst Case" volt. tolerance curves

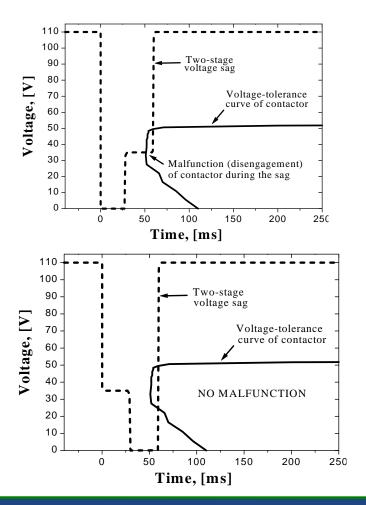


Compare Different Manufacturers
Purchase Suitable Piece of Equipment

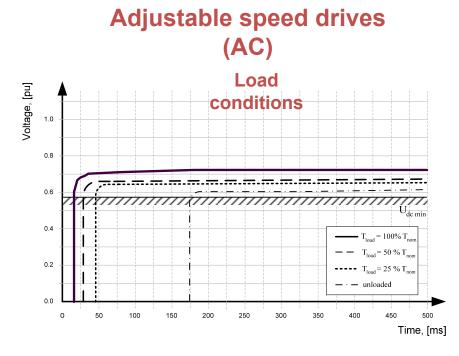
AC Contactors: Point on Wave of Dip Initiation

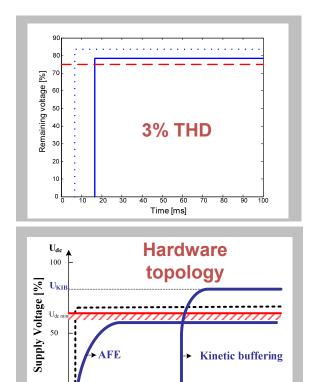


AC Contactors: Dip Shape (Multi-stage Dips)



Parameters Impacting the Behaviour





0.5

Time [s]

0.02

1.5

Parameters impacting the behaviour

- Both manufacturers and end-users should understand the actual impact of dip events on different types equipment
- The design of new equipment should be modified in accordance with this understanding
- Testing: What Parameters to Test Against?
- Research questions:
 - Reclosing of protective devices and multi-stage dips
 - Influence of pre-dip voltage supply conditions



Assessment of Process Immunity

Gathering information on dip immunity of a wide variety of processes:

- Difficult: Not enough information available
- Each process considered as unique
- Formulation of a general framework

Useful inputs

- Electrical engineers do not have all the knowledge
- Identification of critical devices: "trivial" devices often forgotten (sensors, ice-cube relays, control equipment...)
- Two general types of processes: "slow" and "fast" \rightarrow



Process Immunity Time Concept

- Process parameters need to be kept within specs – equipment is just a tool to do so!
- List ALL equipment (actuators, controls, protection)
- How fast do process parameters vary?
 - Electrical engineers, process & process control engineers, instrumentation engineers, ... need to join forces
 - Interruptions easier to test & worst case
 - Past disturbances records, simulations



Process Immunity Time Concept

Procedure:

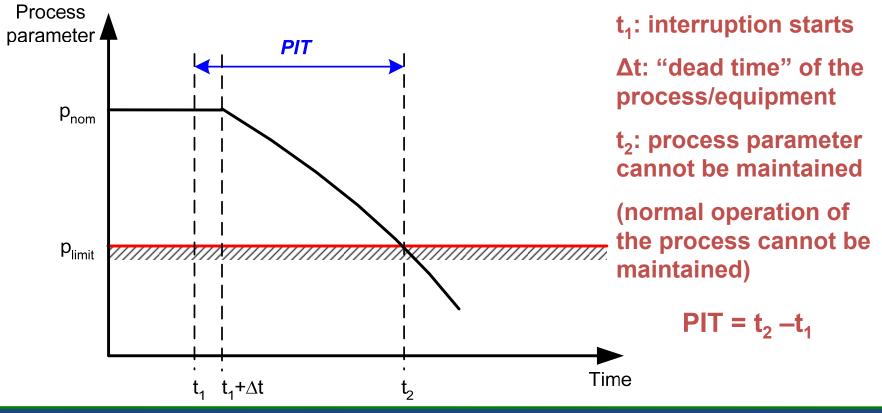
- 1. List all equipment
- 2. Split the process in functional units or parts
- 3. Link relevant equipment to specific process parameters
- 4. Establish the nominal, upper and lower limits for each process parameter
- 5. Determine PIT (e.g. against interruptions)
- 6. Identification of critical process parameters and critical equipment



Process Immunity Time Concept

Process Immunity Time

- Related to equipment controlling/maintaining a parameter





PIT Example: Reactor

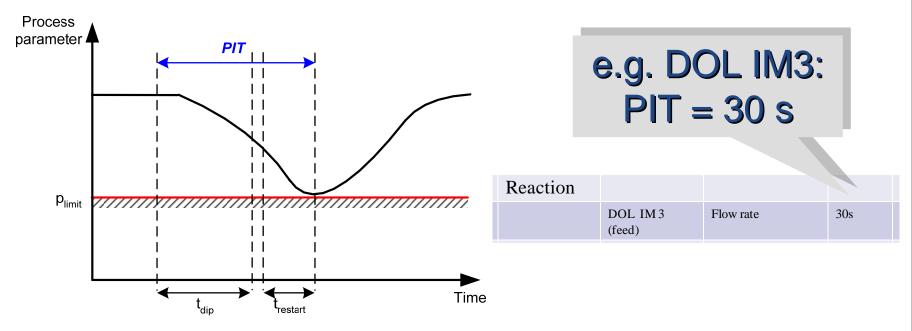
LEVEL 1	LEVEL 2	LEVEL 3	Process parameter	PIT	Priority	Action
Reactor						
	Cooling					
		DOL IM 1 (water)	Reactor cooling water temp	5s	4	Restart 1
		Oil pump	Oil pressure	1,5s	2	Crucial
		DOL IM 2 – fan	Cooling of the water circuit	3min	7	Restart 3
	Reaction					
		DOL IM 3 (feed)	Flow rate	30s	6	Restart 2
		ASD 1 (mixer)	Reaction time	6s	5	Restart
		ASD 2 (air)	% O ₂	2s	3	Mitigate
	Control					
		Temperature sensor	Reactor temperature	1 h	8	
		Oxygen measurement	% O ₂	1s	1	Mitigate
		PLC with UPS		1 h	8	



How to Use PIT to Analyze/Improve Processes

• "High" PIT (PIT > typical dip duration):

- Equipment mitigation not critical
- Can be stopped (at dip detection) and restarted





How to Use PIT to Analyze/Improve Processes

• "Low" PIT (PIT < typical dip duration):

- Equipment can not be stopped and restarted
- Ride-through is essential
- Knowledge of individual equipment behaviour under dip conditions is required

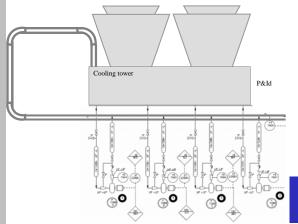
e.g. Oxigen
measurement:
PIT = 1 s

Oxygen	% O ₂	1s
measurement		

- Interaction with manufactures required
 - Other piece of equipment
 - Install more buffer in the process?



PIT Example: Cooling Tower



LEVEL 1	LEVEL 2	LEVEL 3	Process parameter	PIT	Priority	Action
Cooling system						
	Cooling Tower					
		Cooling water pump	T $_{cooling water}$	10 s	1	Mitigate
		Air fans	$T_{coolingwater}$	15 min	3	Restart
		Chemical dosing pumps		1 h	>1h	Restart
	Air compressor	Airbuffer	Q air	30s	2	
		Internal compressor cooling control	$Q_{\text{ cooling water}}$	3 s	1	



Conclusions

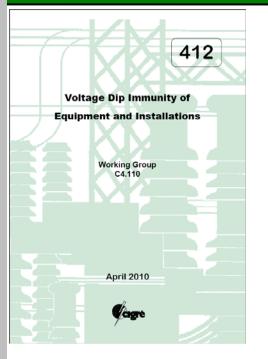
Equipment Immunity

- Voltage-supply, equipment-specific & non-electric factors/parameters of influence
- Wide range in equipment responses & behaviour!

Processes

- Definition of the PIT concept
 - All equipment should be considered
 - Engineers from different disciplines should join forces and learn from each other
 - Ongoing activities to validate the framework





The report can be obtained in electronic format for free from: <u>www.uie.org;</u>

a hardcopy can be purchased from www.e-cigre.org CIGRE/CIRED/UIE Joint Working Group C4.110

Voltage Dip Immunity of

Equipment and Installations

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The contribution from S.C. Vegunta, University of Manchester, is acknowledged

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ISBN: 978-2-85873-099-5

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